

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 862.C2261		APPLICATION NO. 09/877,092	
<div style="border: 1px solid black; border-radius: 50%; padding: 10px; display: inline-block;"> DEC 15 2005 <small>RECEIVED</small> </div>				APPLICANT Takashi Arai			
				FILING DATE June 11, 2001		GROUP N.Y.A.	
IDC-US Ref -10				U.S. PATENT DOCUMENTS			
EXAMINER INITIAL	NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
<i>mf</i>	3,268,639	08/23/66	Taft	264	78		
<i>mf</i>	3,384,691	05/21/68	Weissman et al.	264	47		
<i>mf</i>	3,796,779	03/12/74	Greenberg	264	50		
<i>mf</i>	4,473,665	09/25/84	Martini-Vvedensky et al.	521	79		
<i>mf</i>	5,158,986	10/27/92	Cha et al.	521	82		
<i>mf</i>	5,160,674	11/03/92	Colton et al.	264	50		
<i>mf</i>	5,334,356	08/02/94	Baldwin et al.	422	133		
<i>mf</i>	5,571,848	11/05/96	Mortensen et al.	521	61		
<i>mf</i>	5,866,053	02/02/99	Park et al.	264	50		
<i>mf</i>	4,360,484 44/20/02	11/23/82	Rubens	264	28		
IDC-For Ref -8				FOREIGN PATENT DOCUMENTS			
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
<i>mf</i>	JP 54-128728	10/05/79	Japan			Abstract	
<i>mf</i>	JP 49-111615	10/24/74	Japan			Abstract	
<i>mf</i>	JP 8-300392	11/19/96	Japan			Abstract	
<i>mf</i>	JP 10-24436	01/27/98	Japan			Abstract	
<i>mf</i>	JP 7-232358	09/05/95	Japan			Abstract	
<i>mf</i>	JP 9-48039	02/18/97	Japan			Abstract	
<i>mf</i>	JP 2000-25066	01/25/00	Japan			Abstract	
<i>mf</i>	EP 0662 383 A1	07/12/95	EPO				
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER <i>mf</i>				DATE CONSIDERED <i>1/4/06</i>			

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